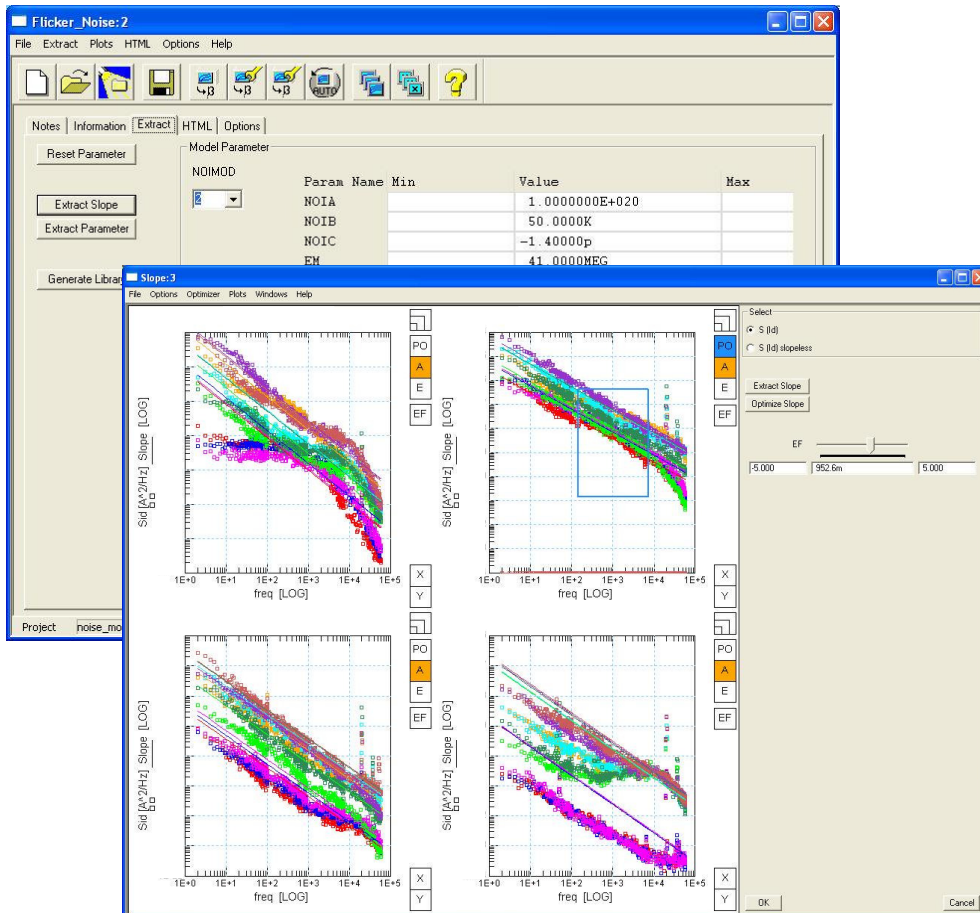


Flicker Noise Modeling System



A complete industry proven solution for flicker noise measurement and parameter extraction.

- Highly efficient measurements through intelligent control of the Low Noise Amplifier.
- Supports the parameter extraction for a wide range of MOS, BJT, diode and resistor models.

Features of the Flicker Noise Modeling System

Measurement Module

- Automatic measurements of all programmed DC operating points of one device through the intelligent adaption of LNA amplification.
- Expert measurement mode for a fully control of the LNA to perform any kind of measurements.
- Export of measured data files into IC-CAP .mdm or Excel format.
- High quality 1Hz filter to support different input resistances.

Extraction Module

- Intuitive user interface for both, extractions and measurements.
- The extractions support the following models: MOS (PSP, BSIM3, BSIM4, BSIM3SOI, BSIM4SOI), BJT (Spice GP), Miscellaneous (Resistors and Diodes).
- Extractions take into account different devices simultaneously to generate highly scalable models.
- The software is running under Agilent Technologies IC-CAP on Windows, Linux or Solaris.
- Fully automatic documentation feature to generate ready to use web documents.
- Online help system and a detailed guidance through all steps of the measurement and extraction procedures.



System Content

- A modified Stanford Research Low Noise Amplifier Sr570 to enable the automatic control of the amplification.
- National Instruments NI CV232A GPIB/RS232 converter
- High quality 1Hz filter
- Measurement and parameter extraction software
- Detailed documentation
- If required, AdMOS can provide all necessary cables, connectors for Cascade Microtech or Suss probe stations.
- A three days training either in the AdMOS lab or at the customers site including a system setup and introduction to measurement and parameter extraction.

Solution Prerequisites

For the Flicker Noise Modeling System, the user must already have Agilent Technologies IC-CAP products 85199A with the appropriate measurement drivers 85199C (DC) and 85199G (Noise). Furthermore, an Agilent Dynamic Signal Analyzer 35670A and a DC Analyzer (e.g. Agilent 4156 or Agilent E5270) is required.

Other Services

AdMOS provides a wide range of modeling services. For more information, please visit our website on www.admos.de

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